SCLS041B - DECEMBER 1982 - REVISED MAY 1997

- 8-Bit Serial-In, Parallel-Out Shift
- High-Current 3-State Outputs Can Drive up to 15 LSTTL Loads
- Shift Register Has Direct Clear
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
 300-mil DIPs

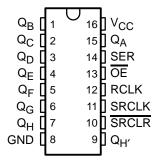
description

The 'HC595 contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state outputs. Separate clocks are provided for both the shift and storage register. The shift register has a direct overriding clear (SRCLR) input, serial (SER) input, and serial outputs for cascading.

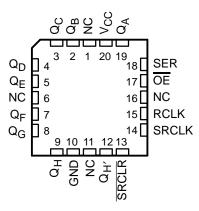
Both the shift register clock (RCLK) and storage register clock (SRCLK) are positive-edge triggered. If both clocks are connected together, the shift register is always one clock pulse ahead of the storage register.

The SN54HC595 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC595 is characterized for operation from –40°C to 85°C.

SN54HC595 . . . J OR W PACKAGE SN74HC595 . . . D OR N PACKAGE (TOP VIEW)



SN54HC595 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

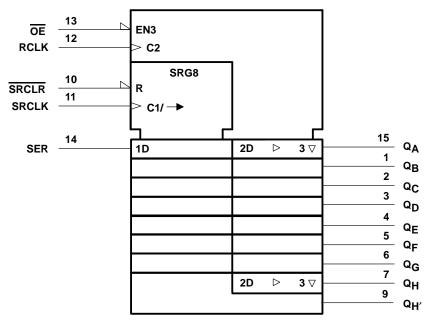


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SN54HC595, SN74HC595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS SCLS041B – DECEMBER 1982 – REVISED MAY 1997

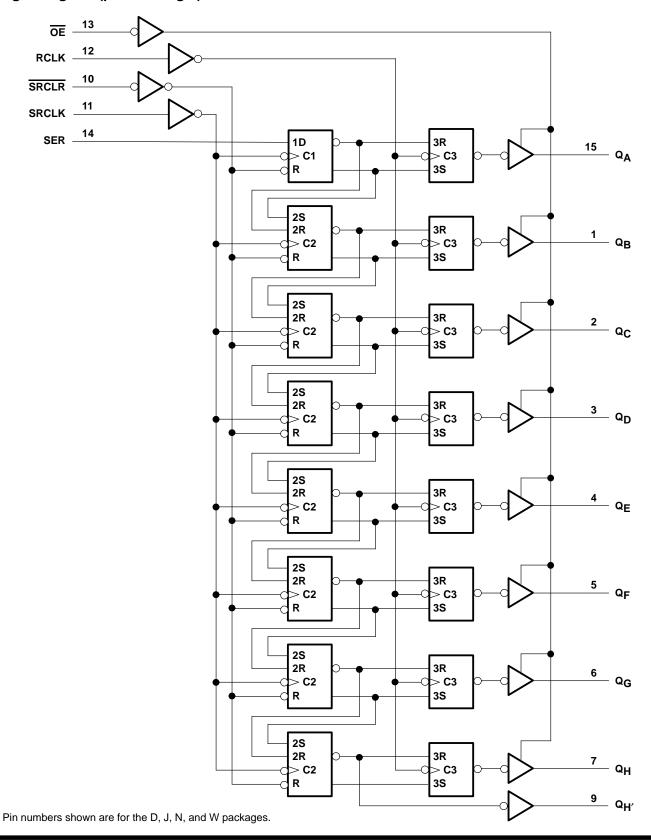
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.



logic diagram (positive logic)





SN54HC595, SN74HC595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS

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absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}	0.5 V to	ว 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20) mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20) mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35	5 mA
Continuous current through V _{CC} or GND	±70) mA
Package thermal impedance, θ _{JA} (see Note 2): D package		
N package		
Storage temperature range, T _{sto}	-65°C to 15	50°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			SI	N54HC59	95	SN74HC595		5	UNIT	
			MIN	MIN NOM MAX MIN NOM				MAX		
VCC	Supply voltage		2	5	6	2	5	6	V	
		V _{CC} = 2 V	1.5			1.5				
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V	
		V _{CC} = 6 V	4.2			4.2				
	Low-level input voltage	V _{CC} = 2 V	0		0.5	0		0.5		
V_{IL}		V _{CC} = 4.5 V	0		1.35	0		1.35	V	
		VCC = 6 V	0		1.8	0		1.8		
VI	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		VCC	0		VCC	V	
		V _{CC} = 2 V	0		1000	0		1000	ns	
tt‡	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	0		500		
		VCC = 6 V	0		400	0		400		
TA	Operating free-air temperature		-55		125	-40		85	°C	

[‡] If this device is used in the threshold region (from V_{IL}max = 0.5 V to V_{IH}min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t_t = 1000 ns and V_{CC} = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	T _A = 25°C			SN54H	IC595	SN74HC595		UNIT
FARAMETER 1231 CONDITIONS		Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
Voн	VI = VIH or VIL	$Q_{H'}$, $I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		V
		Q_A-Q_H , $I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$Q_{H'}$, $I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
		$Q_{A}-Q_{H}$, $I_{OH} = -7.8 \text{ mA}$		5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
VOL		$Q_{H'}$, $I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	V
		Q_A-Q_H , $I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
		$Q_{H'}$, $I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
		Q_A-Q_H , $I_{OL} = 7.8 \text{ mA}$	O V		0.15	0.26		0.4		0.33	
lį	VI = ACC or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	VO = VCC or 0		6 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

SN54HC595, SN74HC595 8-BIT SHIFT REGISTERS WITH 3-STATE OUTPUT REGISTERS SCLS041B - DECEMBER 1982 - REVISED MAY 1997

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	T _A =	25°C	SN54HC595		SN74HC595		UNIT	
			Vcc -	MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V	0	6	0	4.2	0	5		
fclock	Clock frequency		4.5 V	0	31	0	21	0	25	MHz	
			6 V	0	36	0	25	0	29		
			2 V	80		120		100			
		SRCLK or RCLK high or low	4.5 V	16		24		20			
	Pulse duration		6 V	14		20		17		20	
t _W	Fuise duration		2 V	80		120		100		ns	
		SRCLR low	4.5 V	16		24		20			
			6 V	14		20		17			
		SER before SRCLK↑	2 V	100		150		125			
			4.5 V	20		30		25			
			6 V	17		25		21			
		SRCLK↑ before RCLK↑†	2 V	75		113		94			
			4.5 V	15		23		19			
	Catua tima		6 V	13		19		16		ns	
t _{su}	Setup time		2 V	50		75		65			
		SRCLR low before RCLK↑	4.5 V	10		15		13			
			6 V	9		13		11			
			2 V	50		75		60			
		SRCLR high (inactive) before SRCLK↑	4.5 V	10		15		12			
			6 V	9		13		11			
		-	2 V	0		0		0			
th	Hold time, SER af	ter SRCLK↑	4.5 V	0		0		0		ns	
			6 V	0		0		0			

[†] This setup time ensures the output register sees stable data from the shift-register outputs. The clocks may be tied together, in which case the output register is one clock pulse behind the shift register.



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switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	T,	Δ = 25°C	;	SN54H	C595	SN74H	UNIT	
PARAMETER	(INPUT)		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	6	26		4.2		5		
f _{max}			4.5 V	31	38		21		25		MHz
			6 V	36	42		25		29		
			2 V		50	160		240		200	
	SRCLK	$Q_{H'}$	4.5 V		17	32		48		40	
			6 V		14	27		41		34	ns
^t pd			2 V		50	150		225		187	115
	RCLK	Q _A –Q _H	4.5 V		17	30		45		37	
			6 V		14	26		38		32	
	SRCLR	Q _H ′	2 V		51	175		261		219	
tPHL			4.5 V		18	35		52		44	ns
			6 V		15	30		44		37	
			2 V		40	150		225		187	
t _{en}	ŌĒ	Q _A –Q _H	4.5 V		15	30		45		37	ns
			6 V		13	26		38		32	
			2 V		42	200		300		250	
^t dis	OE	Q _A –Q _H	4.5 V		23	40		60		50	ns
			6 V		20	34		51		43	
			2 V		28	60		90		75	
		Q _A –Q _H	4.5 V		8	12		18		15	1
.			6 V		6	10		15		13	
t _t			2 V		28	75		110		95	ns
		$Q_{H'}$	4.5 V		8	15		22		19	
			6 V		6	13		19		16	

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

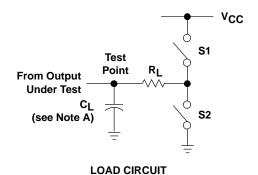
DADAMETED	PARAMETER FROM TO V		Vaa	T,	գ = 25°C	;	SN54H	C595	SN74H	C595	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
			2 V		60	200		300		250		
t _{pd}	RCLK	Q _A –Q _H	4.5 V		22	40		60		50	ns	
			6 V		19	34		51		43		
			2 V		70 200 298		250					
t _{en}	ŌĒ	Q _A –Q _H	Q _A –Q _H	4.5 V		23	40		60		50	ns
						6 V		19	34		51	
tt		Q _A –Q _H		2 V		45	210		315		265	
			4.5 V		17	42		63		53	ns	
			6 V		13	36		53		45		

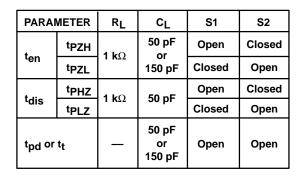
operating characteristics, $T_A = 25^{\circ}C$

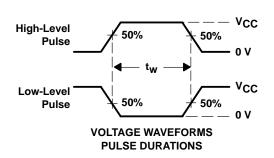
	PARAMETER	TEST CONDITIONS	TYP	UNIT	
C _{pd}	Power dissipation capacitance	No load	400	pF	

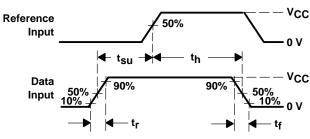


PARAMETER MEASUREMENT INFORMATION

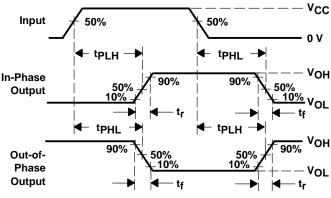


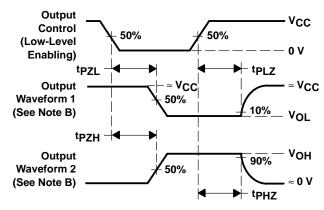






VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
- D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLZ and tpHZ are the same as tdis.
- G. tpZL and tpZH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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